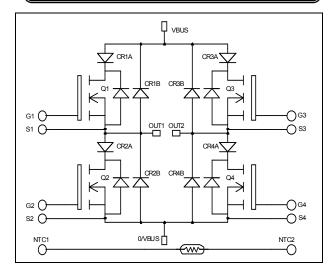
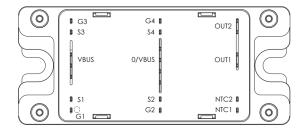


Full bridge Series & SiC parallel diodes MOSFET Power Module





$$\begin{split} V_{DSS} &= 1000V \\ R_{DSon} &= 450 m\Omega \ typ \ @ \ Tj = 25^{\circ}C \\ I_D &= 18A \ @ \ Tc = 25^{\circ}C \end{split}$$

Application

- Motor control
- Switched Mode Power Supplies
- Uninterruptible Power Supplies

Features

- Power MOS 7[®] MOSFETs
 - Low R_{DSon}
 - Low input and Miller capacitance
 - Low gate charge
 - Avalanche energy rated

• Parallel SiC Schottky Diode

- Zero reverse recovery
- Zero forward recovery
- Temperature Independent switching behavior
- Positive temperature coefficient on VF
- Kelvin source for easy drive
- Very low stray inductance
 - Symmetrical design
 - Lead frames for power connections
- Internal thermistor for temperature monitoring
- High level of integration

Benefits

- Outstanding performance at high frequency operation
- Direct mounting to heatsink (isolated package)
- Low junction to case thermal resistance
- Solderable terminals both for power and signal for easy PCB mounting
- Low profile
- RoHS Compliant

All ratings (a) $T_i = 25^{\circ}$ C unless otherwise specified

Absolute maximum ratings

Symbol	Parameter		Max ratings	Unit
$V_{ m DSS}$	Drain - Source Breakdown Voltage		1000	V
Ţ	Continuous Drain Current	$T_c = 25$ °C	18	
I_D		$T_c = 80$ °C	14	A
I_{DM}	Pulsed Drain current	72		
V_{GS}	Gate - Source Voltage		±30	V
R _{DSon}	Drain - Source ON Resistance		540	mΩ
P_{D}	Maximum Power Dissipation	$T_c = 25$ °C	357	W
I_{AR}	Avalanche current (repetitive and non repetitive)		18	Α
E _{AR}	Repetitive Avalanche Energy		50	ma I
E_{AS}	Single Pulse Avalanche Energy		2500	mJ

CAUTION: These Devices are sensitive to Electrostatic Discharge. Proper Handling Procedures Should Be Followed. See application note APT0502 on www.microsemi.com



Electrical Characteristics

Symbol	Characteristic	Test Conditions		Min	Тур	Max	Unit
I_{DSS}	Zero Gate Voltage Drain Current	$V_{GS} = 0V, V_{DS} = 1000V$	$T_j = 25$ °C			100	4
		$V_{GS} = 0V, V_{DS} = 800V$	$T_j = 125$ °C			500	μΑ
R _{DS(on)}	Drain – Source on Resistance	$V_{GS} = 10V, I_D = 9A$			450	540	mΩ
$V_{GS(th)}$	Gate Threshold Voltage	$V_{GS} = V_{DS}, I_{D} = 2.5 \text{m/s}$	1	3		5	V
I_{GSS}	Gate – Source Leakage Current	$V_{GS} = \pm 30 \text{ V}, V_{DS} = 0 \text{ V}$	V			±100	nA

Dynamic Characteristics

•	Characteristic	Test Conditions	Min	Тур	Max	Unit
C_{iss}	Input Capacitance	$V_{GS} = 0V$		4350		
C_{oss}	Output Capacitance	$V_{DS} = 25V$		715		pF
C_{rss}	Reverse Transfer Capacitance	f = 1MHz		120		
Q_{g}	Total gate Charge	$V_{GS} = 10V$		154		
Q_{gs}	Gate – Source Charge	$V_{\text{Bus}} = 500 \text{V}$		26		nC
Q_{gd}	Gate – Drain Charge	$I_D = 18A$		97		
$T_{d(on)}$	Turn-on Delay Time	Inductive switching @ 125°C $V_{GS} = 15V$ $V_{Bus} = 667V$ $I_D = 18A$		10		
T_{r}	Rise Time			12		ns
$T_{d(off)}$	Turn-off Delay Time			121		
T_{f}	Fall Time	$R_G = 5\Omega$		35		
Eon	Turn-on Switching Energy	Inductive switching @ 25°C		383		т.
E_{off}	Turn-off Switching Energy	$V_{GS} = 15V, V_{Bus} = 667V$ $I_D = 18A, R_G = 5\Omega$		380		μJ
Eon	Turn-on Switching Energy	Inductive switching @ 125°C		627		
E _{off}	Turn-off Switching Energy	$V_{GS} = 15V, V_{Bus} = 667V$ $I_D = 18A, R_G = 5\Omega$		451		μJ
R_{thJC}	Junction to Case Thermal Resistance				0.35	°C/W

Series diode ratings and characteristics

Symbol	Characteristic	Test Conditions		Min	Typ	Max	Unit	
V_{RRM}	Maximum Peak Repetitive Reverse Voltage			1000			V	
I_{RM}	Maximum Reverse Leakage Current	$V_R = 1000V$				250	μΑ	
I_F	DC Forward Current		$T_c = 85^{\circ}C$		30		A	
	Diode Forward Voltage	$I_F = 30A$			1.9	2.3		
V_{F}		$I_F = 60A$			2.2		V	
		$I_F = 30A$	$T_j = 125$ °C		1.7			
+	Reverse Recovery Time $I = 20 \text{ A}$		$T_j = 25$ °C		290		ng	
t_{rr}		$T_{j} = 125^{\circ}C$		390		ns		
Qrr	Reverse Recovery Charge	$di/dt = 200A/\mu s$	$di/dt = 200 \text{ A/us} \qquad T_i = 25^\circ$	$di/dt = 200 \text{ A/us}$ $T_i = 25^{\circ}\text{C}$		670		nC
			$T_j = 125$ °C		2350		iiC	
R_{thJC}	Junction to Case Thermal Resistance					1.2	°C/W	



Parallel SiC diode ratings and characteristics

Symbol	Characteristic	Test Conditions		Min	Typ	Max	Unit
V_{RRM}	Maximum Peak Repetitive Reverse Voltage			1200			V
I_{RRM}	Maximum Reverse Leakage Current	V _R =1200V	$T_{j} = 25^{\circ}C$ $T_{j} = 175^{\circ}C$		100	400 2000	μΑ
I_{F}	DC Forward Current		Tc = 100°C		10		A
$V_{\rm F}$	Diode Forward Voltage	$I_F = 10A$	$T_{j} = 25^{\circ}C$ $T_{j} = 175^{\circ}C$		1.6 2.6	1.8 3.0	V
Qc	Total Capacitive Charge	$I_F = 10A, V_R = 1200V$ di/dt = 800A/ μ s			56		nC
Q	Total Capacitance	$f = 1MHz, V_R = 200V$	= 200V	90	90		F
		$f = 1MHz, V_R =$	= 400V		66		pF
R_{thJC}	Junction to Case Thermal Resistance					1.5	°C/W

Thermal and package characteristics

Symbol	l Characteristic			Min	Max	Unit
V_{ISOL}	RMS Isolation Voltage, any terminal to case t =1 min, 50/60Hz			4000		V
T_{J}	Operating junction temperature range			-40	150	
T_{JOP}	Recommended junction temperature under switching conditions			-40	T _J max -25	°C
T_{STG}	Storage Temperature Range			-40	125	
$T_{\rm C}$	Operating Case Temperature			-40	100	
Torque	Mounting torque	To Heatsink	M5	2.5	4.7	N.m
Wt	Package Weight				160	g

Temperature sensor NTC (see application note APT0406 on www.microsemi.com).

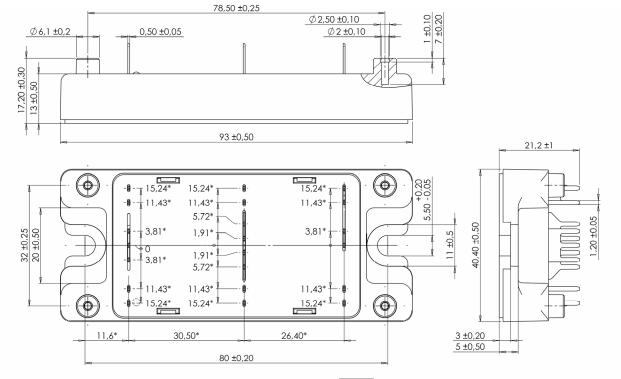
Symbol	Characteristic		Min	Typ	Max	Unit
R ₂₅	Resistance @ 25°C	C		50		kΩ
$\Delta R_{25}/R_{25}$				5		%
$B_{25/85}$	$T_{25} = 298.15 \text{ K}$			3952		K
$\Delta \mathrm{B/B}$		T _C =100°C		4		%

$$R_T = \frac{R_{25}}{\exp \left[B_{25/85} \left(\frac{1}{T_{-5}} - \frac{1}{T} \right) \right]}$$
 T: Thermistor temperature R_T: Thermistor value at T

3 – 9



SP4 Package outline (dimensions in mm)

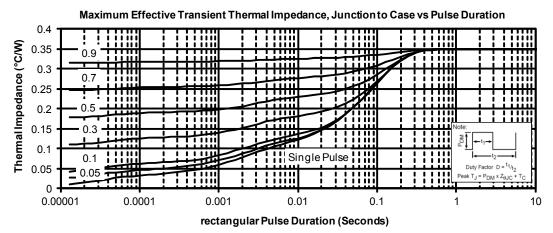


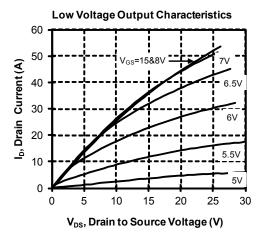
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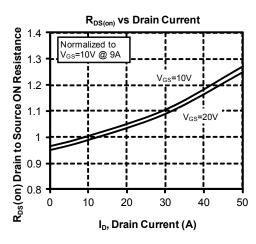
See application note APT0501 - Mounting Instructions for SP4 Power Modules on www.microsemi.com

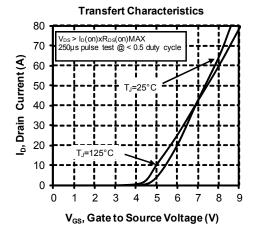


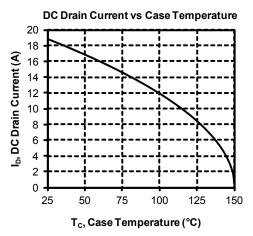
Typical MOSFET Performance Curve





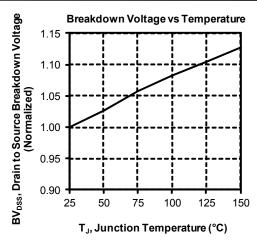


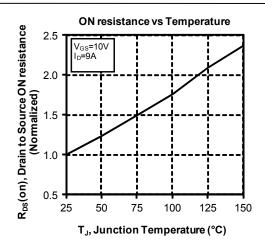


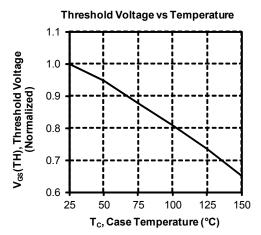


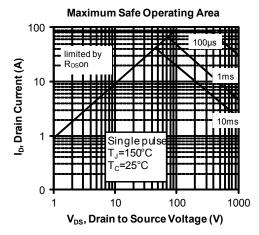
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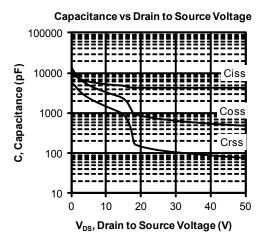


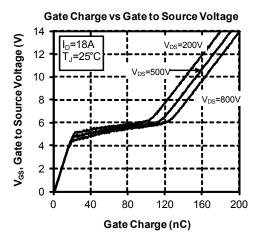




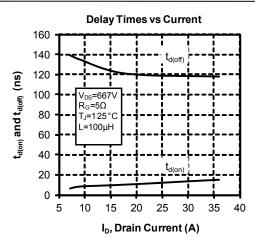


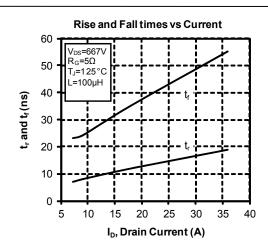


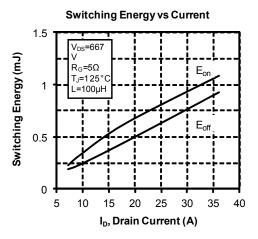


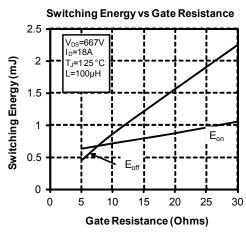


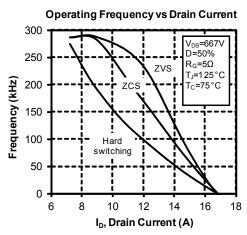






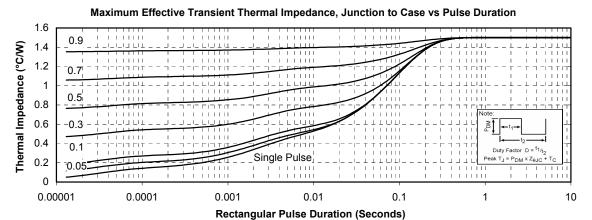


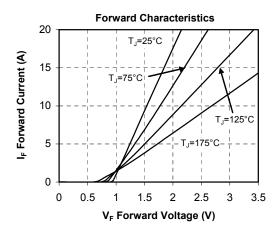


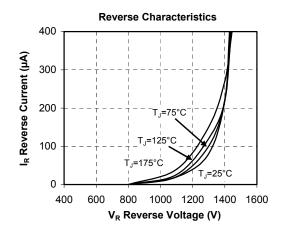


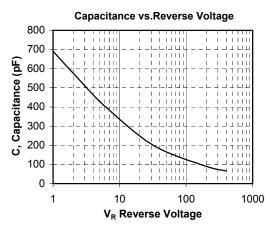


Typical SiC Diode Performance Curve









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